

Testing Advanced Semiconductor Packages, LEDs, MEMS Sensors & Traditional ICs

High-Performance Strip Test Handler in Strip Format or Device Carrier

- Delivers industry-leading index times, with strip handling down to 2.0 seconds and device handling as fast as 180 milliseconds
- Supports full tri-temperature range from -45°C to $+160^{\circ}\text{C}$, with and without LN₂. Extended low-temperature option down to -55°C
- Option for closed-loop control with embedded watchdog temperature sensors located in the contactor near the DUT for enhanced accuracy and protection
- Supports in-process testing via a SMEMA interface, allowing seamless integration into automated production lines
- Includes automatic contact cleaning using an ACC block and brush system, ensuring consistent contact performance and reduced maintenance.
- Factory Automation with Industrial Mobile Robot (IMR) communicates via SECS-GEM and requires no additional connecting hardware (E84 Standard)
- PAICe™ Digital Twin Platform provides real-time equipment monitoring and data analytics for Industry 4.0/Factory Automation

Jaguar

High-Performance Strip Test Handler



PAICe
DIGITAL TWIN PLATFORM™

High Yield resulting in Excellent OEE

- Enables extremely fast and easy kit conversion through an intuitive quick-lock function, minimizing downtime
- MUBA >1,000 strips >4 hour operation without operator assist possible
- Temperature accuracy +/- 2°C, supported by closed loop temperature system and intelligent contactor
- Wide package range; Leaded and leadless with the ability to handle all common types of strip and different type of strip input and output
- Options for both Loader/Unloader types, including stacked and slotted, and field upgrade possible
- Enables semi-automated pin-to-pad alignment, improving setup efficiency while maintaining precise device contact
- Includes RMS (Recipe Management System) capabilities for easy creation, storage, and recall of test configurations, ensuring repeatability and reducing setup time
- Designed to be Auto-DIB exchange ready

Digital Twin Platform

- Real-time equipment monitoring and management
- Preventative maintenance
- Central recipe management
- Optimized yield and defect detection through real-time Artificial Intelligence inspection
- Knowledge database and unified reports



Advanced Configuration Options

- 3D package test
- Substrate based, bare die handling
- Vacuum contacting
- Single device in a carrier or strip handling

Optional Modules

- Stacked or slotted loader/unloader
- High Parallel Power (HPP)
- Various sensor test applications available

All specifications are subject to change without notification and are for reference only. For detailed performance specifications, please contact Cohu.

REV20260529

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